Special Issue

Advanced Optical Imaging and Sensing Techniques for Smart Farming and Food Processing

Message from the Guest Editor

The techniques for optical measurements of raw agricultural materials and foods have been advanced in recent years to the point where the conventional assessments and monitoring for farming and food processing are becoming more digital and intelligent.

We invite you to contribute original research articles or critical survey/review articles highlighting the needs for smart farming and food processing with optical signal measurement and analysis. Potential topics in the area of optical imaging and sensing include, but are not limited to innovative techniques and instrument designs for optical imaging or sensing, novel data analysis methods, agriculture and food monitoring, detection and characterization of quality and safety attributes in agricultural and food products, high throughput sensing, and autonomous system.

Guest Editor

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Deadline for manuscript submissions

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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